

# N-Channel 60 V (D-S) MOSFET

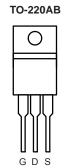
PRODUCT SUMMARY						
V <sub>DS</sub> (V)	$V_{DS}(V)$ $R_{DS(on)}(\Omega)$					
60	0.024 at V <sub>GS</sub> = 10 V	50				
60	0.028 at V <sub>GS</sub> = 4.5 V	40				

#### **FEATURES**

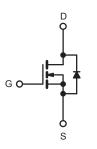
- Halogen-free According to IEC 61249-2-21 Definition
- Surface Mount
- Available in Tape and Reel
- Dynamic dV/dt Rating
- Logic-Level Gate Drive
- Fast Switching
- Compliant to RoHS Directive 2002/95/EC







Top View



N-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATINGS</b> (T <sub>C</sub> = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			$V_{DS}$	60	W	
Gate-Source Voltage			$V_{GS}$	± 20	V	
Continuous Drain Current <sup>f</sup>	V <sub>GS</sub> at 10 V	$T_{\rm C} = 25  ^{\circ}{\rm C}$ $T_{\rm C} = 100  ^{\circ}{\rm C}$	L	50		
Continuous Drain Current	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 100 °C	ID	36	Α	
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	200		
Linear Derating Factor				1.0	- W/°C	
Linear Derating Factor (PCB Mount)e		0.025	VV/ C			
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	400	mJ	
Maximum Power Dissipation	T <sub>C</sub> = 25 °C			150	W	
Maximum Power Dissipation (PCB Mount)e	T <sub>A</sub> = 25 °C		P <sub>D</sub>	3.7	"	
Peak Diode Recovery dV/dtc			dV/dt	4.5	V/ns	
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 175	- °C	
Soldering Recommendations (Peak Temperature) <sup>d</sup> for 10 s				300 <sup>d</sup>	]	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b.  $V_{DD} = 25$  V, starting  $T_J = 25$  °C, L = 179  $\mu$ H,  $R_g = 25$   $\Omega$ ,  $I_{AS} = 51$  A (see fig. 12). c.  $I_{SD} \le 51$  A,  $I_{AS} = 51$

- d. 1.6 mm from case.
- e. When mounted on 1" square PCB (FR-4 or G-10 material).
- f. Current limited by the package, (die current = 51 A).



THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	TYP.	MAX.	UNIT		
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	62			
Maximum Junction-to-Ambient (PCB Mount) <sup>a</sup>	R <sub>thJA</sub>	-	40	°C/W		
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	1.0			

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Note
a. When mounted on 1" square PCB (FR-4 or G-10 material).

<b>SPECIFICATIONS</b> (T <sub>J</sub> = 25 °C, u	nless otherw	ise noted)					
PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static				•			
Drain-Source Breakdown Voltage	$V_{DS}$	V <sub>GS</sub> = 0, I <sub>D</sub> = 250 μA		60	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference to 25 °C, I <sub>D</sub> = 1 mA		-	0.070	-	V/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_D = 250 \mu A$		1.0	-	2.5	
Gate-Source Leakage	I <sub>GSS</sub>	V <sub>GS</sub> = ± 10 V		-	-	± 100	nA
Zana Oata Valta va Busin Ouwant		V <sub>DS</sub> = 60 V, V <sub>GS</sub> = 0 V		-	-	25	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 48 V	, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 150 °C	-	-	250	μA
Buris Co. and Co. Olaha Burisha	Б	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 21 A <sup>b</sup>	-	0.024	-	
Drain-Source On-State Resistance	$R_{DS(on)}$	V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 15 A <sup>b</sup>	-	0.028	-	Ω
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub> :	= 25 V, I <sub>D</sub> = 21A <sup>b</sup>	23	-	-	S
Dynamic				•	•		
Input Capacitance	C <sub>iss</sub>		V	-	190		
Output Capacitance	C <sub>oss</sub>	$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$ f = 1.0  MHz,  see fig. 5		-	920	-	pF
Reverse Transfer Capacitance	C <sub>rss</sub>			-	170	-	
Total Gate Charge	Qg			-	-	66	
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 5.0 V	$V_{GS} = 5.0 \text{ V}$ $I_D = 51 \text{ A}, V_{DS} = 48 \text{ V},$ see fig. 6 and 13 <sup>b</sup>		-	12	nC
Gate-Drain Charge	Q <sub>gd</sub>		See lig. 6 and 16	-	-	43	
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{DD}$ = 30 V, $I_{D}$ = 51 A, $R_{g}$ = 4.6 Ω, $R_{D}$ = 0.56 Ω, see fig. 10 <sup>b</sup>		-	17	-	- ns
Rise Time	t <sub>r</sub>			-	230	-	
Turn-Off Delay Time	t <sub>d(off)</sub>			-	2	-	
Fall Time	t <sub>f</sub>			-	110	-	
Internal Drain Inductance	L <sub>D</sub>	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	-11
Internal Source Inductance	L <sub>S</sub>			-	7.5	=	nH
Drain-Source Body Diode Characteristic	cs						
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	50 <sup>c</sup>	A
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>			-	-	200	
Body Diode Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C	$C$ , $I_S = 51 \text{ A}$ , $V_{GS} = 0 \text{ V}^b$	-	-	2.5	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> = 25 °C, I <sub>F</sub> = 51 A, dl/dt = 100 A/μs <sup>b</sup>		-	130	180	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			-	0.84	1.3	μC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic tu	-on is dor	minated b	y L <sub>S</sub> and	L <sub>D</sub> )	

### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
  b. Pulse width ≤ 300 μs; duty cycle ≤ 2 %.
  c. Current limited by the package, (Die Current = 51 A).



### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

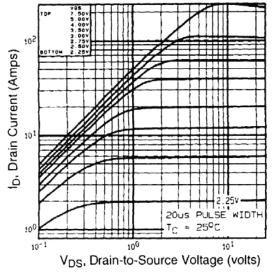


Fig. 1 - Typical Output Characteristics,  $T_C = 25$  °C

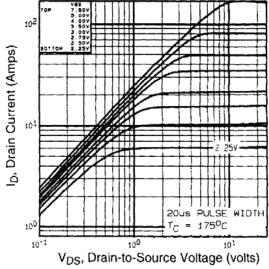


Fig. 2 - Typical Output Characteristics,  $T_C = 150 \, ^{\circ}\text{C}$ 

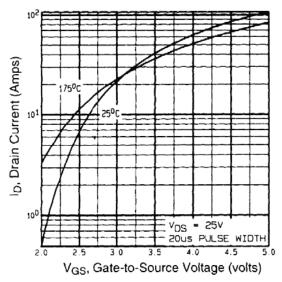


Fig. 3 - Typical Transfer Characteristics

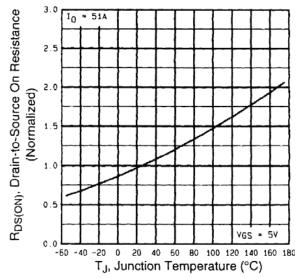


Fig. 4 - Normalized On-Resistance vs. Temperature



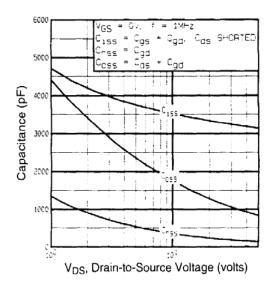


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

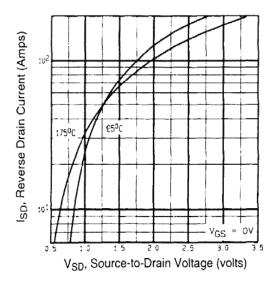


Fig. 7 - Typical Source-Drain Diode Forward Voltage

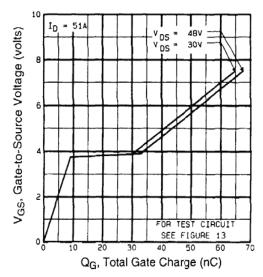


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

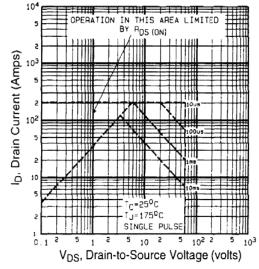


Fig. 8 - Maximum Safe Operating Area



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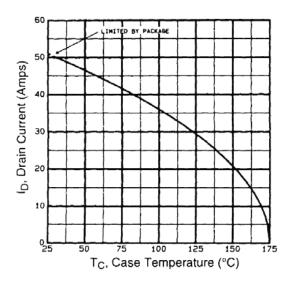


Fig. 9 - Maximum Drain Current vs. Case Temperature

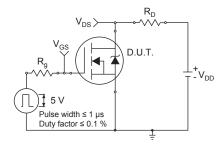


Fig. 10a - Switching Time Test Circuit

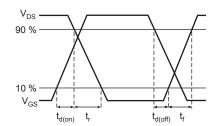


Fig. 10b - Switching Time Waveforms

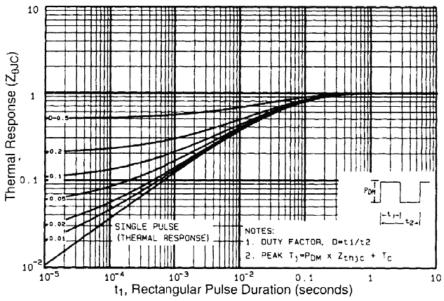
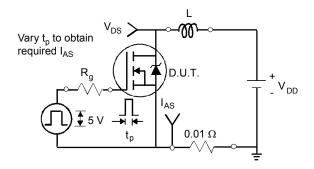


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case





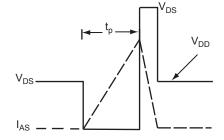


Fig. 12a - Unclamped Inductive Test Circuit

Fig. 12b - Unclamped Inductive Waveforms

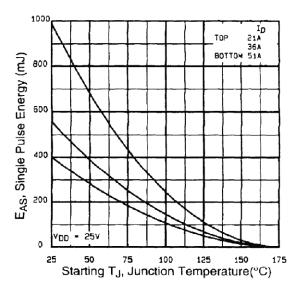


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

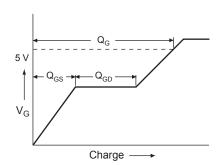


Fig. 13a - Basic Gate Charge Waveform

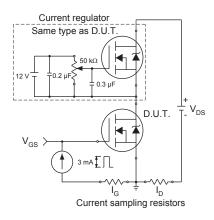
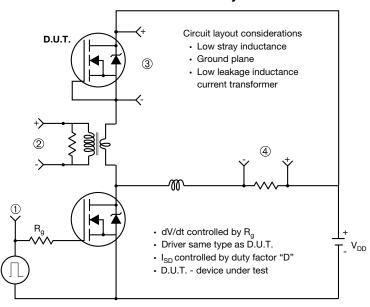
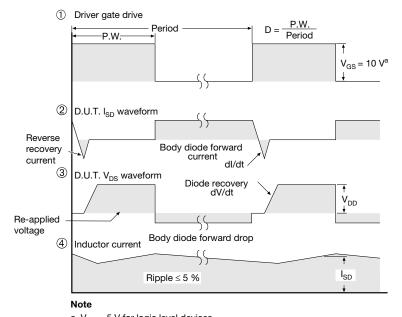


Fig. 13b - Gate Charge Test Circuit



#### Peak Diode Recovery dV/dt Test Circuit

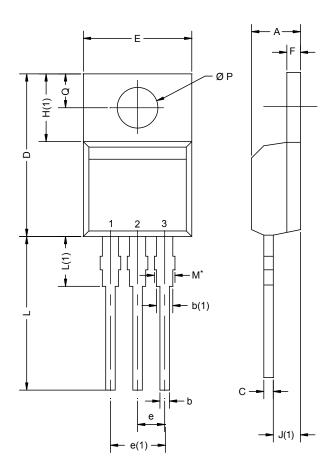




a.  $V_{GS}$  = 5 V for logic level devices Fig. 14 - For N-Channel



## **TO-220AB**



	MILLIM	IETERS	INC	HES		
DIM.	MIN.	MAX.	MIN.	MAX.		
А	4.25	4.65	0.167	0.183		
b	0.69	1.01	0.027	0.040		
b(1)	1.20	1.73	0.047	0.068		
С	0.36	0.61	0.014	0.024		
D	14.85	15.49	0.585	0.610		
Е	10.04	10.51	0.395	0.414		
е	2.41	2.67	0.095	0.105		
e(1)	4.88	5.28	0.192	0.208		
F	1.14	1.40	0.045	0.055		
H(1)	6.09	6.48	0.240	0.255		
J(1)	2.41	2.92	0.095	0.115		
L	13.35	14.02	0.526	0.552		
L(1)	3.32	3.82	0.131	0.150		
ØР	3.54	3.94	0.139	0.155		
Q	2.60	3.00	0.102	0.118		
ECN: X12-0208-Rev. N. 08-Oct-12						

ECN: X12-0208-Rev. N, 08-Oct-12 DWG: 5471

## Notes

 $^{\star}$  M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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